Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/679,320	LEE ET AL.	
Examiner	**Art Unit**	
Harold Kim	2181	

SEARCHED			
Class	Subclass	Date	Examiner
710	2, 8, 36, 38, 72,300	4/2/2006	HK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPAT, USPGPUB, JPO, EPO, IEEE, NPL, PLUS, see attached search note, inventor search on eDAN	4/2/2006	HK